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FORM HDP-1449 (Based on Form PTO-1449)

**PATENT AND TRADEMARK OFFICE  
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Sheet 1 of 1

ATTORNEY DOCKET NO.

SERIAL NO.

8959-000044/US

10/612,334

APPLICANT

Horst WITTUR et al.

FILING DATE

GROUP

July 2, 2003

3654

**U.S. PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date

**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
WO 94/20770		<del>BR 940560770-2</del>	09-15-1994	<del>Brazil</del> Switzerland		Abstract	
		JP 6-263369	09-20-1994	Japan		Abstract	
		JP 7-267534	10-17-1995	Japan		Abstract	
		JP 8-113888	05-07-1996	Japan		Abstract	
		JP 9-095879	04-08-1997	Japan		Abstract	
		JP 10-007351	01-13-1998	Japan		Abstract	
		JP 2702074	01-21-1998	Japan		Abstract	
		JP 11-310372	11-09-1999	Japan		Abstract	
		JP 2002-179355	06-26-2002	Japan		Abstract	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

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Ref. Desig.	Examiner's Initials	
		<del>Japanese Office Action dated December 21, 2006, for corresponding Patent Application No. 2002-554612</del>
		<del>Japanese Office Action dated December 13, 2007, for corresponding Patent Application No. 2002-554612</del>
		No translations from Japanese to English provided.

JAC/LFG/mas

Examiner:	/Stefan Kruer/	Date Considered:	12/06/2010
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